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Parallel Tests

... be used to **test** correlation within, and between, **random** number sequences [13, 16].

Consider two **random** sequences X and Y and define the **exponential** sum cross ...

spring.cs.fsu.edu/Version1.0/paper/node17.html - 10k - [Cached](#) - [Similar pages](#)

Random Number Generation

... and DIEHARD, systems for **testing** the quality of ... Fortran codes for generating **random** numbers according ... distributions, including normal, **exponential**, and Poisson ...

www2.toki.or.id/book/AlgDesignManual/BOOK/BOOK4/NODE142.HTM - 25k - [Cached](#) - [Similar pages](#)

Lilliefors Test of Exponentiality

... for Normality; **Test** for Uniform Distribution; **Testing** Poisson Process; **Test** for **Randomness**; **Testing** Several Proportions; **Testing** the ...

home.ubalt.edu/ntsbarsh/Business-stat/otherapplets/Lilliefors.htm - 31k - [Cached](#) - [Similar pages](#)

Forecasting by Smoothing

... They are used to filter **random** "white noise" from the data, to make the ... **Exponential** Smoothing: This is a very popular scheme to produce a smoothed Time Series. ...

home.ubalt.edu/ntsbarsh/Business-stat/otherapplets/ForecastSmo.htm - 42k - [Cached](#) - [Similar pages](#)

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P-values

... c 2 value, df n, P-value. **Exponential** Density. Enter the rate l and **random** duration

(t), and then click the Compute button. l, t, P-value. Fisher's F-Density. ...

www.cs.sun.ac.za/~lynette/simulation/harsham/pvalues.htm - 33k - [Cached](#) - [Similar pages](#)

Kohler | Statistics for Business and Economics

... 10.8 **EXPONENTIAL** PROBABILITY TABLES. 10.9 **EXPONENTIAL** PROBABILITIES AND COMPUTER PROGRAMS. ... APPLICATION 14.3 **Testing Random Digits for Randomness**. ...

www.swlearning.com/quant/kohler/stat/aboutproduct/excel_toc3.html - 28k - [Cached](#) - [Similar pages](#)

Statistics Paper I & II

... Problems in life **testing**, Censored and truncated experiments for **exponential** models.

2.4 SAMPLING:- Simple **random** sampling systematic and stratified, Ratio and ...

www.tn.gov.in/tnpsc/statisticsone.htm - 13k - [Cached](#) - [Similar pages](#)

Chapter Summary

... **Testing for Randomness**. Regression-Based Trend Models. The **Random** Walk Model.

Autoregression Models. Moving Averages. **Exponential** Smoothing. Seasonal Models. ...

www.duxbury.com/statistics_d/templates/student_resources/059438367X/chapter_summary/ch_summary.html - 7k - [Cached](#) - [Similar pages](#)

random.com.hr - Diehard

... THE 3DSPHERES TEST Choose 4000 **random** points in a ... close to) exponentially distributed with mean $120\pi/3$. Thus the radius cubed is **exponential** with mean ...

random.com.hr/products/random/Diehard.html - 21k - [Cached](#) - [Similar pages](#)

Biostatistical Software

... **random** sampling, stratified **random** sampling, ratio ... Functions: Cauchy, Exponentiated

Exponential, Extreme, Laplace ... Likelihood ratio **test**: Rectangular distribution ...

pages.prodigy.net/johnsonp12/homepage.html - 39k - [Cached](#) - [Similar pages](#)



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Statistical Signal and Array Processing, 1996. Proceedings., 8th IEEE Signal Processing Workshop on (Cat. No.96TB10004 , 24-26 June 1996

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6 The B Itzmann entropy and randomness tests*Gacs, P.;*

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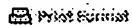
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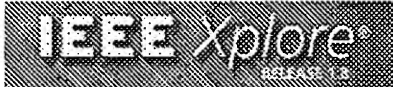
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